

$750 \text{ MHz}, 16 \times 8$ Analog Crosspoint Switch

ADV3224/ADV3225

FEATURES

 16×8 high speed, nonblocking switch array Pinout and functionally equivalent to the AD8110/AD8111 Drop-in compatible with the ADV3228/ADV3229 8 \times 8 array Complete solution

Buffered inputs

Programmable high impedance outputs

8 output amplifiers, G = +1 (ADV3224), G = +2 (ADV3225)

Drives 150 Ω loads Operates on ±5 V supplies

Low power: 0.5 W

Excellent ac performance

-3 dB bandwidth

200 mV p-p: 1200 MHz (ADV3224), 900 MHz (ADV3225)

2 V p-p: 750 MHz (ADV3224), 850 MHz (ADV3225)

0.5 dB flatness (2 V p-p)

250 MHz (ADV3224), 235 MHz (ADV3225)

Slew rate: 2500 V/µs

Serial or parallel programming of switch array

72-lead LFCSP (10 mm × 10 mm)

APPLICATIONS

Routing of high speed signals including Video (NTSC, PAL, S, SECAM, YUV, RGB) Compressed video (MPEG, wavelet) 3-level digital video (HDB3)

Data communications Telecommunications

GENERAL DESCRIPTION

The ADV3224/ADV3225 are high speed 16×8 analog crosspoint switch matrices. They offer a -3 dB signal bandwidth of greater than 750 MHz and a high slew rate of greater than 2500 V/ μ s.

The ADV3224/ADV3225 include eight independent output buffers that can be placed into a high impedance state for paralleling crosspoint outputs to prevent off channels from loading the output bus. The ADV3224 has a gain of +1 and the ADV3225 has a gain of +2, and they both operate on voltage

FUNCTIONAL BLOCK DIAGRAM

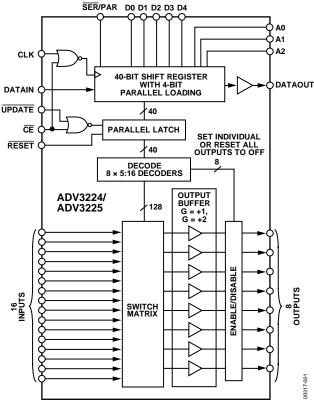


Figure 1.

supplies of ± 5 V. Channel switching is performed via a serial digital control that can accommodate the daisy chaining of several devices or via a parallel control to allow updating of an individual output without reprogramming the entire array.

The ADV3224/ADV3225 are available in the 72-lead LFCSP package over the extended industrial temperature range of -40°C to +85°C.

TABLE OF CONTENTS

| Features | 1 |
|-----------------------------------|---|
| Applications | |
| Functional Block Diagram | 1 |
| General Description | 1 |
| Revision History | 2 |
| Specifications | 3 |
| Timing Characteristics (Serial) | 5 |
| Logic Levels | 5 |
| Timing Characteristics (Parallel) | 6 |
| Absolute Maximum Ratings | 7 |
| Thermal Resistance | 7 |
| Power Dissipation | 7 |
| ESD Caution | 7 |
| | |
| REVISION HISTORY | |

| Pin Configuration and Function Descriptions | 8 |
|---|----|
| Truth Table and Logic Diagram | 10 |
| Typical Performance Characteristics | 11 |
| Circuit Diagrams | 20 |
| Theory of Operation | 21 |
| Applications Information | 22 |
| Serial Programming | 22 |
| Parallel Programming | 22 |
| Power-On Reset | 23 |
| Gain Selection | 23 |
| Creating Larger Crosspoint Arrays | 23 |
| Outline Dimensions | 24 |
| Ordering Guide | 24 |
| | |

REVISION HISTORY

| 12/10—Rev. 0 to Rev. A | |
|---------------------------|----|
| Changes to Ordering Guide | 24 |

11/10—Revision 0: Initial Version

SPECIFICATIONS

 $\rm V_S = \pm 5$ V, $\rm T_A = 25^{\circ} C, \, R_L = 150 \; \Omega,$ unless otherwise noted.

Table 1.

| | | AD | ADV3224 | | | ADV322 | 25 | |
|--------------------------------|---|-------|---------|-----|-----|--------|-----|---------|
| Parameter | Test Conditions/Comments | Min 1 | Тур | Max | Min | Тур | Max | Unit |
| DYNAMIC PERFORMANCE | | | | | | | | |
| –3 dB Bandwidth | 200 mV p-p | 1 | 1200 | | | 900 | | MHz |
| | 2 V p-p | 7 | 750 | | | 850 | | MHz |
| Gain Flatness | 0.1 dB, 2 V p-p | Ţ | 55 | | | 50 | | MHz |
| | 0.5 dB, 2 V p-p | 2 | 250 | | | 235 | | MHz |
| Propagation Delay | 2 V p-p | (| 0.6 | | | 0.6 | | ns |
| Settling Time | 1%, 2 V step | 3 | 3 | | | 3 | | ns |
| Slew Rate | 2 V step, peak | 2 | 2500 | | | 2500 | | V/µs |
| NOISE/DISTORTION PERFORMANCE | | | | | | | | |
| Differential Gain Error | NTSC or PAL | (| 0.01 | | | 0.02 | | % |
| Differential Phase Error | NTSC or PAL | (| 0.01 | | | 0.02 | | Degrees |
| Crosstalk, All Hostile, RTO | f = 100 MHz | - | -45 | | | -45 | | dB |
| | f = 5 MHz | - | -87 | | | -70 | | dB |
| Off Isolation, Input to Output | f = 100 MHz, one channel | - | -80 | | | -87 | | dB |
| OIP2 | $f = 100 \text{ MHz}, R_L = 100 \Omega$ | | | | | 38 | | dBm |
| | $f = 500 \text{ MHz}, R_L = 100 \Omega$ | | | | | 15 | | dBm |
| OIP3 | $f = 100 \text{ MHz}, R_L = 100 \Omega$ | | | | | 32 | | dBm |
| | $f = 500 \text{ MHz}, R_L = 100 \Omega$ | | | | | 7 | | dBm |
| Output 1 dB Compression Point | $f = 100 \text{ MHz}, R_L = 100 \Omega$ | | | | | 19 | | dBm |
| | $f = 500 \text{ MHz}, R_L = 100 \Omega$ | | | | | 10 | | dBm |
| Input Voltage Noise Density | 50 MHz | 1 | 18 | | | 18 | | nV/√Hz |
| DC PERFORMANCE | | | | | | | | |
| Gain Error | | (| 0.1 | 0.5 | | 0.2 | 1.5 | % |
| Gain Matching | Channel-to-channel | | | 0.5 | | | 1.5 | % |
| Gain Temperature Coefficient | | (| 0.5 | | | 5 | | ppm/°C |
| OUTPUT CHARACTERISTICS | | | | | | | | |
| Output Resistance | DC, enabled | (| 0.2 | | | 0.2 | | Ω |
| | DC, disabled | 1 | 15 | | | 8 | | ΜΩ |
| Output Disabled Capacitance | | 2 | 2.2 | | | 2.6 | | pF |
| Output Leakage Current | Output disabled | (| 0.5 | | | 0.5 | | μΑ |
| Output Voltage Range | No load | = | ±3 | | | ±3 | | V |
| | $R_L = 150 \Omega$ | = | ±2.8 | | | ±2.8 | | V |
| Short-Circuit Current | | | 55 | | | 55 | | mA |
| INPUT CHARACTERISTICS | | | | | | | | |
| Input Offset Voltage | Worst case (all configurations) | = | ±5 | | | ±5 | | mV |
| Input Offset Voltage Drift | | | 5 | | | 5 | | μV/°C |
| Input Voltage Range | | = | ±3 | | | ±1.5 | | V |
| Input Capacitance | Any switch configuration | 1 | 1.8 | | | 1.8 | | pF |
| Input Resistance | | 2 | 2 | | | 2 | | ΜΩ |
| Input Bias Current | Any switch configuration | = | ±1 | | | ±1 | | μΑ |
| SWITCHING CHARACTERISTICS | | | | | | | | |
| Enable/Disable Time | 50% UPDATE to 1% settling | 2 | 20 | | | 20 | | ns |
| Switching Time, 2 V Step | 50% UPDATE to 1% settling | 2 | 20 | | | 20 | | ns |
| Switching Transient (Glitch) | | | 25 | | | 50 | | mV p-p |

| | | | ADV322 | 4 | | ADV322 | 5 | |
|-----------------------------|--------------------------------|------|--------|------|------|--------|------|------|
| Parameter | Test Conditions/Comments | Min | Тур | Max | Min | Тур | Max | Unit |
| POWER SUPPLIES | | | | | | | | |
| Supply Current | AVCC, outputs enabled, no load | | 52 | 70 | | 58 | 70 | mA |
| | AVCC, outputs disabled | | 12 | 18 | | 13 | 18 | mA |
| | AVEE, outputs enabled, no load | | 52 | 70 | | 58 | 70 | mA |
| | AVEE, outputs disabled | | 12 | 18 | | 14 | 18 | mA |
| | DVCC, outputs enabled, no load | | 6 | | | 6 | | mA |
| Supply Voltage Range | | ±4.5 | ±5 | ±5.5 | ±4.5 | ±5 | ±5.5 | V |
| PSRR | DC to 50 kHz, AVCC, AVEE | | <-60 | | | <-60 | | dB |
| | f = 100 kHz, AVCC, AVEE | | -60 | | | -60 | | dB |
| | f = 10 MHz, AVCC | | -48 | | | -35 | | dB |
| | f = 10 MHz, AVEE | | -35 | | | -55 | | dB |
| | f = 100 MHz, AVCC | | -25 | | | -15 | | dB |
| | f = 100 MHz, AVEE | | -15 | | | -15 | | dB |
| | f = 100 kHz, DVCC | | -90 | | | -90 | | dB |
| OPERATING TEMPERATURE RANGE | | | | | | | | |
| Temperature Range | Operating (still air) | -40 | | +85 | -40 | | +85 | °C |
| Θ_{JA} | Operating (still air) | | 29 | | | 29 | | °C/W |

TIMING CHARACTERISTICS (SERIAL)

Table 2.

| Parameter | Symbol | Min | Тур | Max | Unit |
|---|----------------|-----|-----|-----|------|
| Serial Data Setup Time | t ₁ | 10 | | | ns |
| CLK Pulse Width | t ₂ | 10 | | | ns |
| Serial Data Hold Time | t ₃ | 10 | | | ns |
| CLK Pulse Separation, Serial Mode | t ₄ | 10 | | | ns |
| CLK to UPDATE Delay | t ₅ | 10 | | | ns |
| UPDATE Pulse Width | t ₆ | 10 | | | ns |
| CLK to DATAOUT Valid, Serial Mode | t ₇ | | | 50 | ns |
| Propagation Delay, UPDATE to Switch On or Off | | | 20 | | ns |
| Data Load Time, CLK = 5 MHz, Serial Mode | | | 8 | | μs |
| CLK, UPDATE Rise and Fall Times | | | | 50 | ns |
| RESET Time | | | 30 | | ns |

Timing Diagram—Serial Mode

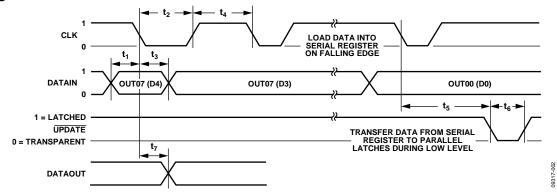


Figure 2. Timing Diagram, Serial Mode

LOGIC LEVELS

Table 3. Logic Levels

| V _{IH} | V _{IL} | V _{OH} | V _{OL} | I _{IH} | I _{IL} | I _{IH} | I _{IL} | I _{OH} | I _{OL} |
|-----------------|-----------------|------------------------|-----------------|-----------------|-----------------|-----------------|-----------------|-----------------|-----------------|
| RESET, SER/PAR, | RESET, SER/PAR, | DATAOUT | DATAOUT | SER/PAR, | SER/PAR, CLK, | RESET | RESET | DATAOUT | DATAOUT |
| CLK, DATAIN, | CLK, DATAIN, | | | CLK, DATAIN, | DATAIN, CE, | | | | |
| CE, UPDATE | CE, UPDATE | | | CE, UPDATE | UPDATE | | | | |
| 2.0 V min | 0.8 V max | 2.4 V min | 0.4 V max | 2 μA max | 2 μA max | 2 μA max | 300 μA max | 3 mA min | 1 mA min |

TIMING CHARACTERISTICS (PARALLEL)

Table 4.

| Parameter | Symbol | Min | Тур | Max | Unit |
|---------------------------------|-----------------|-----|-----|-----|------|
| Parallel Data Setup Time | t _{1d} | 10 | | | ns |
| Address Setup Time | t _{1a} | 10 | | | ns |
| CLK Pulse Width | t ₂ | 10 | | | ns |
| Parallel Data Hold Time | t _{3d} | 10 | | | ns |
| Address Hold Time | t _{3a} | 10 | | | ns |
| CLK Pulse Separation | t ₄ | 20 | | | ns |
| UPDATE Pulse Width | t ₅ | 10 | | | ns |
| CLK, UPDATE Rise and Fall Times | | | | 50 | ns |
| RESET Time | | | 30 | | ns |

Timing Diagram—Parallel Mode

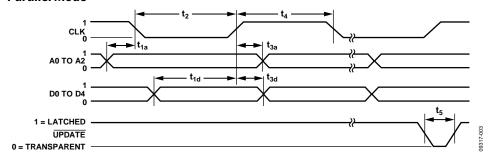


Figure 3. Timing Diagram, Parallel Mode

ABSOLUTE MAXIMUM RATINGS

Table 5.

| Table 5. | |
|---|--------------------------------|
| Parameter | Rating |
| Analog Supply Voltage (AVCC to AVEE) | 11 V |
| Digital Supply Voltage (DVCC to DGND) | 6 V |
| Supply Potential Difference (AVCC – DVCC) | ±0.5 V |
| Ground Potential Difference (AGND – DGND) | ±0.5 V |
| Maximum Potential Difference (DVCC – AVEE) | 6 V |
| Analog Input Voltage | $AVEE < V_{IN} < AVCC$ |
| Digital Input Voltage | $DGND < D_{IN} < DVCC$ |
| Exposed Paddle Voltage | AGND |
| Output Voltage (Disabled Analog Output) | AVEE < V _{OUT} < AVCC |
| Output Short-Circuit | |
| Duration | Momentary |
| Current | Internally limited to 55 mA |
| Temperature | |
| Storage Temperature Range | −65°C to +125°C |
| Operating Temperature Range | −40°C to +85°C |
| Junction Temperature | 150°C |
| Lead Temperature (Soldering, 10 sec) | 300°C |

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

THERMAL RESISTANCE

 θ_{JA} is specified for the worst-case conditions, that is, a device soldered in a circuit board for surface-mount packages.

Table 6. Thermal Resistance

| Package Type | θ_{JA} | θ_{JC} | Unit |
|------------------|---------------|---------------|------|
| 72-Lead LFCSP_VQ | 29 | 0.5 | °C/W |

POWER DISSIPATION

The ADV3224/ADV3225 operate with ± 5 V supplies and can drive loads down to 100 Ω , resulting in a wide range of possible power dissipations. For this reason, extra care must be taken when derating the operating conditions based on ambient temperature.

Packaged in the 72-lead LFCSP, the ADV3224/ADV3225 junction-to-ambient thermal impedance (θ_{JA}) is 29°C/W. For long-term reliability, the maximum allowed junction temperature of the die should not exceed 125°C; even temporarily exceeding this limit can cause a shift in parametric performance due to a change in stresses exerted on the die by the package. Exceeding a junction temperature of 150°C for an extended period can result in device failure. In Figure 4, the curve shows the range of allowed internal die power dissipation that meets these conditions over the -40° C to $+85^{\circ}$ C ambient temperature range. When using Figure 4, do not include the external load power in the maximum power calculation, but do include the load current dropped on the die output transistors.

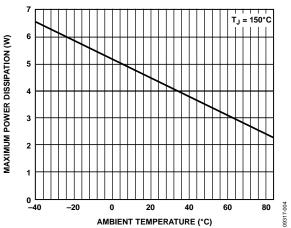


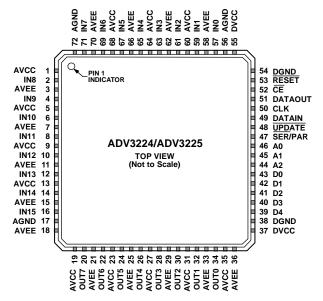
Figure 4. Maximum Die Power Dissipation vs. Ambient Temperature

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



NOTES

1. EXPOSED PADDLE. THE EXPOSED METAL PADDLE ON THE BOTTOM OF THE LFCSP PACKAGE MUST BE SOLDERED TO THE PCB AGND FOR PROPER HEAT DISSIPATION AND FOR NOISE AND MECHANICAL STRENGTH BENEFITS.

Figure 5. Pin Configuration

Table 7. Pin Function Descriptions

| Pin No. | Mnemonic | Description |
|---|----------|-------------------------------------|
| 1, 5, 9, 13, 19, 23, 27, 31, | AVCC | Analog Positive Supply. |
| 35, 60, 64, 68 | | |
| 2 | IN8 | Input Number 8. |
| 3, 7, 11, 15, 18, 21, 25, 29, 33, 36, 58, 62, 66, 70 | AVEE | Analog Negative Supply. |
| 4 | IN9 | Input Number 9. |
| 6 | IN10 | Input Number 10. |
| 8 | IN11 | Input Number 11. |
| 10 | IN12 | Input Number 12. |
| 12 | IN13 | Input Number 13. |
| 14 | IN14 | Input Number 14. |
| 16 | IN15 | Input Number 15. |
| 17, 56, 72 | AGND | Analog Ground. |
| 20 | OUT7 | Output Number 7. |
| 22 | OUT6 | Output Number 6. |
| 24 | OUT5 | Output Number 5. |
| 26 | OUT4 | Output Number 4. |
| 28 | OUT3 | Output Number 3. |
| 30 | OUT2 | Output Number 2. |
| 32 | OUT1 | Output Number 1. |
| 34 | OUT0 | Output Number 0. |
| 37, 55 | DVCC | Digital Positive Supply. |
| 38, 54 | DGND | Digital Ground. |
| 39 | D4 | Parallel Data Input, Output Enable. |
| 40 to 43 | D3 to D0 | Parallel Data Input. |
| 44 to 46 | A2 to A0 | Parallel Output Address Input. |

| Pin No. | Mnemonic | Description |
|---------|---------------|--|
| 47 | SER/PAR | Serial/Parallel Mode Select (Control Pin). |
| 48 | <u>UPDATE</u> | Second Rank Write Strobe (Control Pin). |
| 49 | DATAIN | Serial Data In (Control Pin). |
| 50 | CLK | Serial Data Clock, Parallel First Rank Latch Enable (Control Pin). |
| 51 | DATAOUT | Serial Data Out. |
| 52 | CE | Chip Enable (Control Pin). |
| 53 | RESET | Second Rank Reset (Control Pin). |
| 57 | IN0 | Input Number 0. |
| 59 | IN1 | Input Number 1. |
| 61 | IN2 | Input Number 2. |
| 63 | IN3 | Input Number 3. |
| 65 | IN4 | Input Number 4. |
| 67 | IN5 | Input Number 5. |
| 69 | IN6 | Input Number 6. |
| 71 | IN7 | Input Number 7. |
| | EPAD | Exposed Paddle. The exposed metal paddle on the bottom of the LFCSP package must be soldered to the PCB AGND for proper heat dissipation and for noise and mechanical strength benefits. |

TRUTH TABLE AND LOGIC DIAGRAM

Table 8. Operation Truth Table¹

| CE | UPDATE | CLK | DATAIN | DATAOUT | RESET | SER/PAR | Description | |
|----|--------|-----|--------------------------------|--|-------|---------|---|--|
| 1 | Χ | Χ | Χ | Х | Χ | Χ | No change in logic. | |
| 0 | X | Ł | Data _l ² | Data _{l-80} | Х | 0 | The data on the serial DATAIN line is loaded into the serial register. The first bit clocked into the serial register appears at DATAOUT 40 clock cycles later. | |
| 0 | X | 0 | D0D4 | Not applicable in parallel mode ³ | Х | 1 | The data on the parallel data lines, D0 to D4, are loaded into the 40-bit serial shift register location addressed at A0 to A2. | |
| 0 | 0 | Χ | Х | X | 1 | X | Data in the 40-bit shift register transfers into the parallel latches that control the switch array. Latches are transparent. | |
| X | X | Х | X | X | 0 | X | Asynchronous operation. All outputs are disabled. Second rank latches are cleared. Remainder of logic is unchanged. | |

 $^{^{1}\,\}mathrm{X}$ is don't care.

³ DATAOUT remains active in parallel mode and always reflects the state of the MSB of the serial shift register.

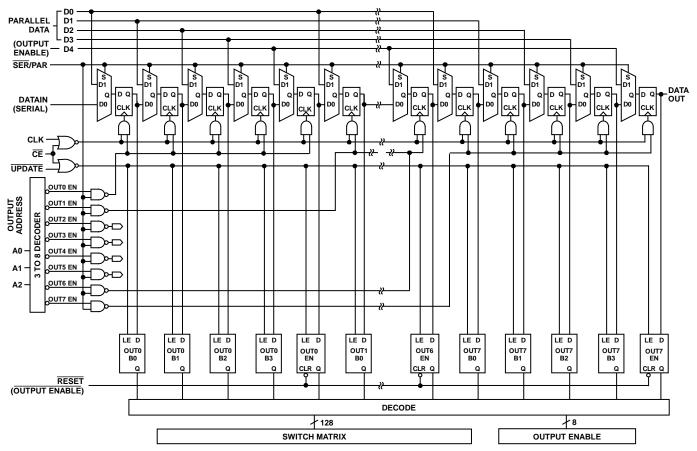


Figure 6. Logic Diagram

² Data_i: serial data.

TYPICAL PERFORMANCE CHARACTERISTICS

 $V_S = \pm 5$ V, $T_A = 25$ °C, $R_L = 150$ Ω , unless otherwise noted. T_{MIN} to $T_{MAX} = -40$ °C to +85°C.

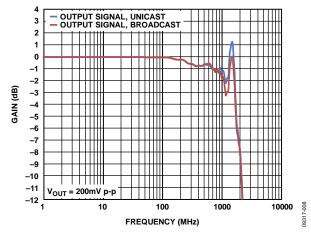


Figure 7. ADV3224 Small Signal Frequency Response

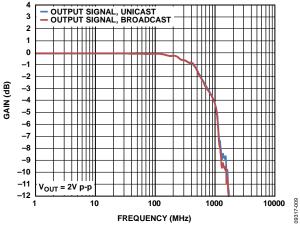


Figure 8. ADV3224 Large Signal Frequency Response

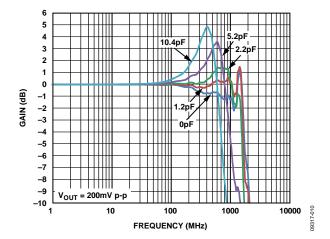


Figure 9. ADV3224 Small Signal Frequency Response with Capacitive Loads

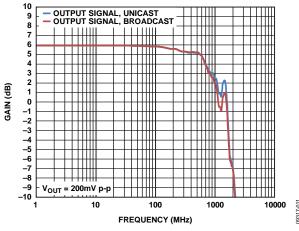


Figure 10. ADV3225 Small Signal Frequency Response

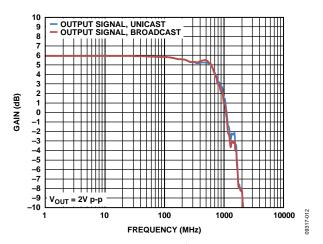


Figure 11. ADV3225 Large Signal Frequency Response

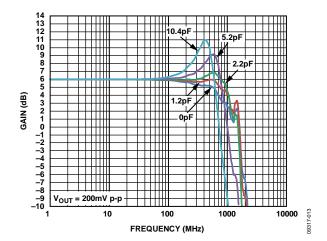


Figure 12. ADV3225 Small Signal Frequency Response with Capacitive Loads

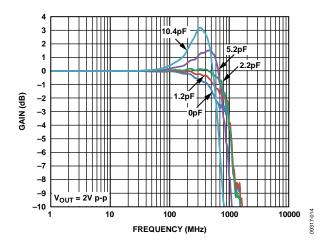


Figure 13. ADV3224 Large Signal Frequency Response with Capacitive Loads

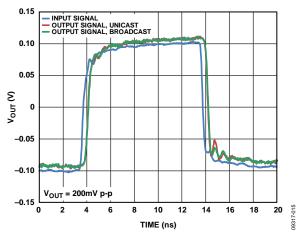


Figure 14. ADV3224 Small Signal Pulse Response

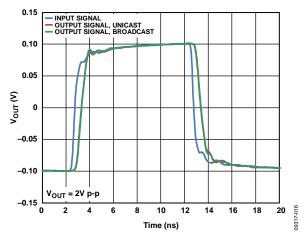


Figure 15. ADV3224 Large Signal Pulse Response

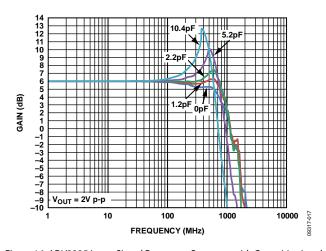


Figure 16. ADV3225 Large Signal Frequency Response with Capacitive Loads

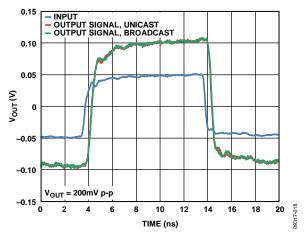


Figure 17. ADV3225 Small Signal Pulse Response

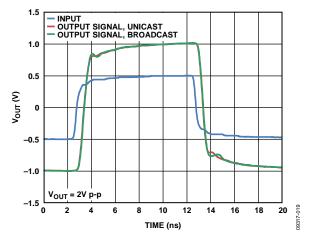


Figure 18. ADV3225 Large Signal Pulse Response

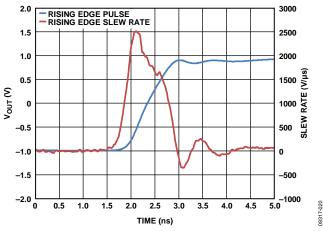


Figure 19. ADV3224 Rising Edge Slew Rate

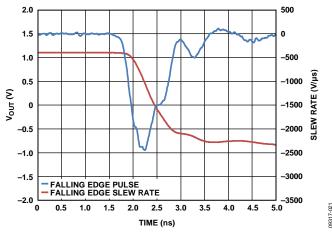


Figure 20. ADV3224 Falling Edge Slew Rate

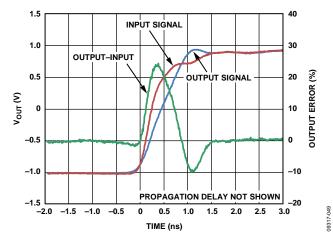


Figure 21. ADV3224 Settling Time

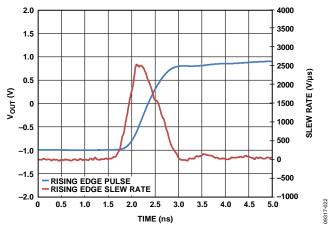


Figure 22. ADV3225 Rising Edge Slew Rate

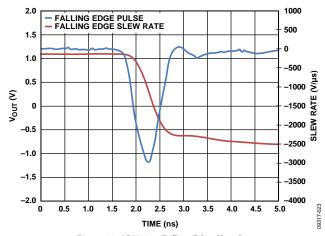


Figure 23. ADV3225 Falling Edge Slew Rate

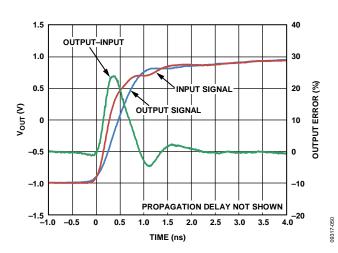


Figure 24. ADV3225 Settling Time

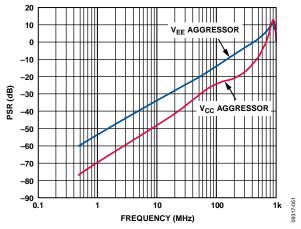


Figure 25. ADV3224 Power Supply Rejection

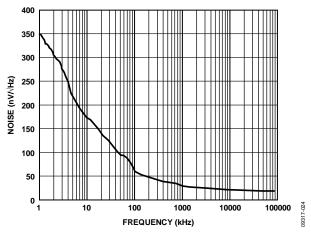


Figure 26. ADV3224 Output Noise Density, 100Ω Load

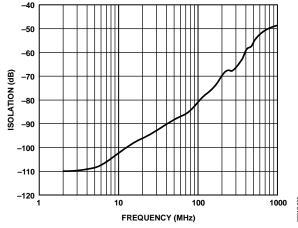


Figure 27. ADV3224 Off Isolation

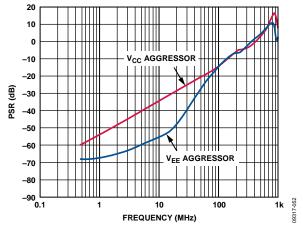


Figure 28. ADV3225 Power Supply Rejection

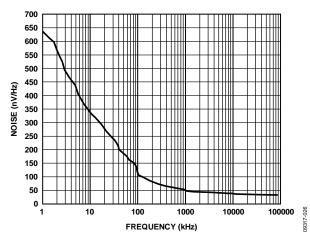


Figure 29. ADV3225 Output Noise Density, 100Ω Load

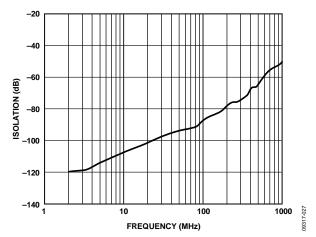


Figure 30. ADV3225 Off Isolation

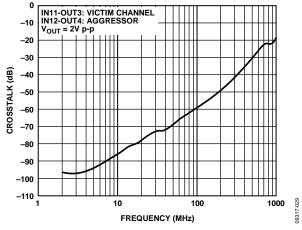


Figure 31. ADV3224 Crosstalk, One Adjacent Channel, RTO

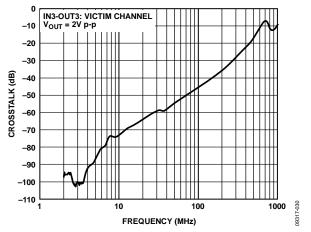


Figure 32. ADV3224 Crosstalk, All Hostile, RTO

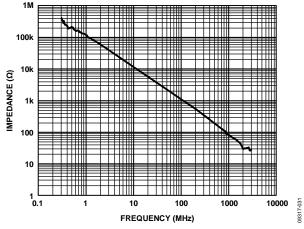


Figure 33. ADV3224 Input Impedance

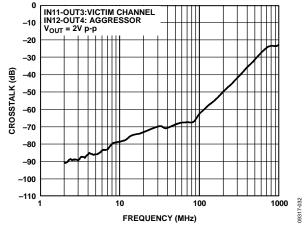


Figure 34. ADV3225 Crosstalk, One Adjacent Channel, RTO

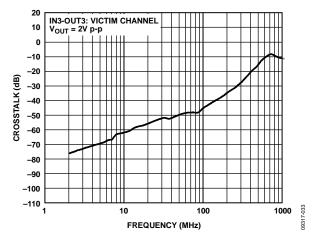


Figure 35. ADV3225 Crosstalk, All Hostile, RTO

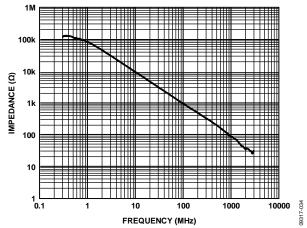


Figure 36. ADV3225 Input Impedance

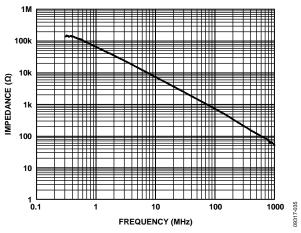


Figure 37. ADV3224 Output Impedance, Disabled

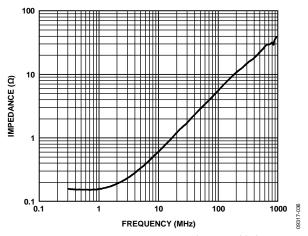


Figure 38. ADV3224 Output Impedance, Enabled

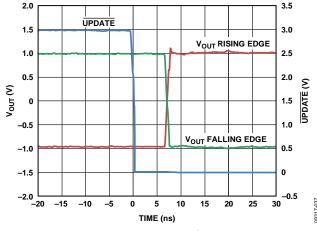


Figure 39. ADV3224 Switching Time

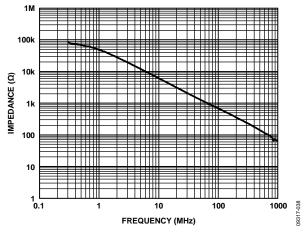


Figure 40. ADV3225 Output Impedance, Disabled

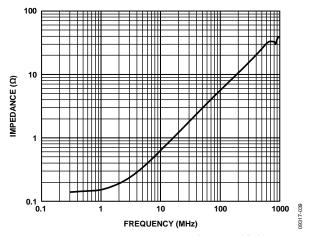


Figure 41. ADV3225 Output Impedance, Enabled

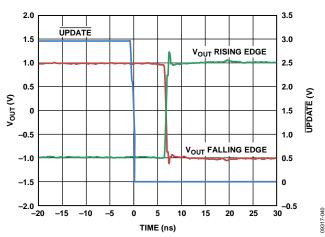


Figure 42. ADV3225 Switching Time

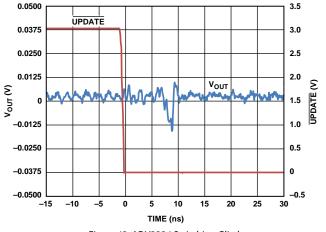


Figure 43. ADV3224 Switching Glitch

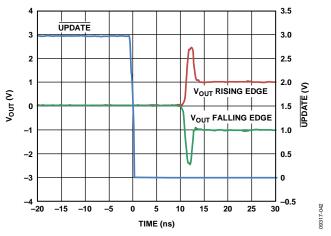


Figure 44. ADV3224 Enable Time

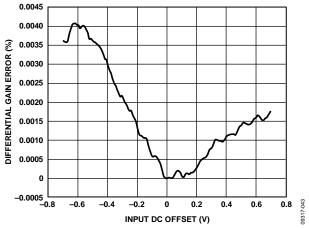


Figure 45. ADV3224 Differential Gain Error

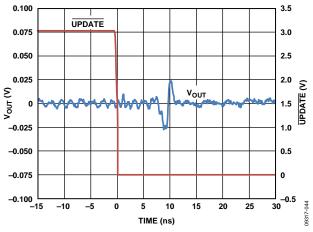


Figure 46. ADV3225 Switching Glitch

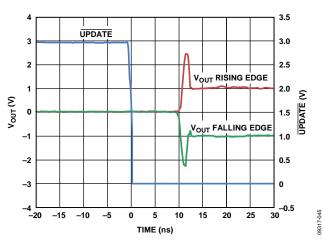


Figure 47. ADV3225 Enable Time

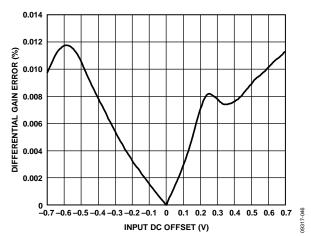


Figure 48. ADV3225 Differential Gain Error

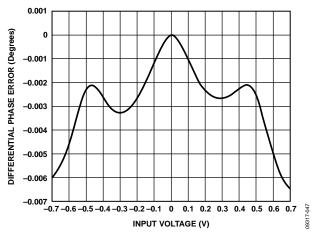


Figure 49. ADV3224 Differential Phase Error

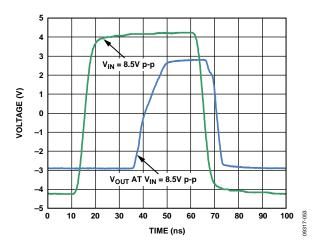


Figure 50. ADV3224 Overdrive Recovery

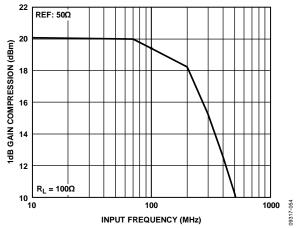


Figure 51. ADV3225 1 dB Gain Compression, 100Ω Load

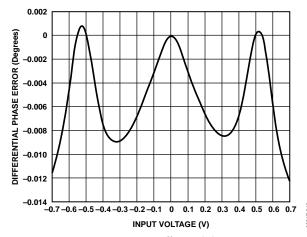


Figure 52. ADV3225 Differential Phase Error

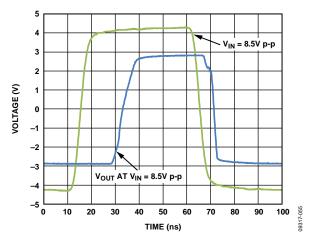


Figure 53. ADV3225 Overdrive Recovery

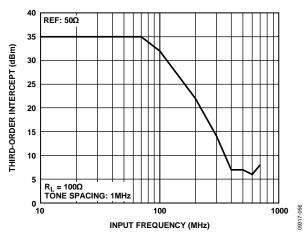


Figure 54. ADV3225 Output Third-Order Intercept, 100 Ω Load

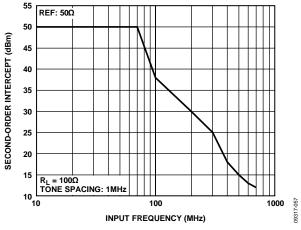


Figure 55. ADV3225 Output Second-Order Intercept, 100 Ω Load

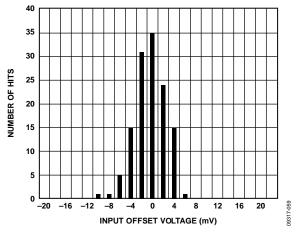


Figure 56. ADV3224 and ADV3225, Input $V_{\rm OS}$ Distribution

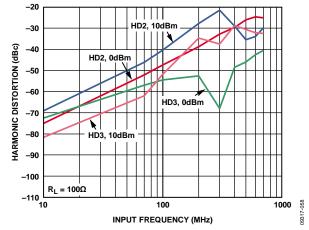


Figure 57. ADV3225 Harmonic Distortion, 100Ω Load

CIRCUIT DIAGRAMS



Figure 58. Analog Input

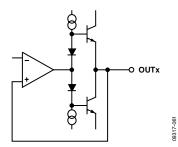


Figure 59. Analog Output Enabled

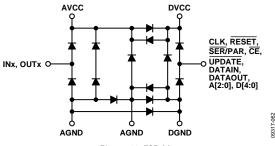


Figure 60. ESD Map

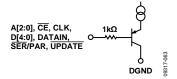


Figure 61. Logic Input

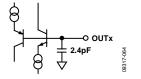


Figure 62. Analog Output Disabled

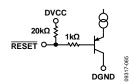


Figure 63. Reset Input

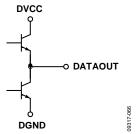


Figure 64. Logic Output

THEORY OF OPERATION

The ADV3224 (G = +1) and ADV3225 (G = +2) are crosspoint arrays with eight outputs, each of which can be connected to any one of 16 inputs. Organized by output row, 16 switchable input transconductance stages are connected to each output buffer to form 16-to-1 multiplexers. There are eight of these multiplexers, each with its inputs wired in parallel, for a total array of 128 transconductance stages forming a multicast-capable crosspoint switch. Each input is buffered and is not loaded by the outputs, simplifying the construction of larger arrays using the ADV3224 or ADV3225 as a building block.

Decoding logic for each output selects one (or none) of the transconductance stages to drive the output stage. The enabled transconductance stage drives the output stage, and feedback forms a closed-loop amplifier. A mask programmable feedback network sets the closed-loop signal gain. For the ADV3224, this gain is +1, and for the ADV3225, this gain is +2.

The output stage of the ADV3224 or ADV3225 is designed for low differential gain and phase error when driving composite video signals. It also provides slew current for a fast pulse response when driving component video signals. Unlike many multiplexer designs, these requirements are balanced such that large signal bandwidth is very similar to small signal bandwidth. The design load is 150 Ω , but provisions are made to drive loads as low as 100 Ω when on-chip power dissipation limits are not exceeded.

The outputs of the ADV3224/ADV3225 can be disabled to minimize on-chip power dissipation. When disabled, there is no feedback network loading the output. This high disabled output impedance allows multiple ICs to be bussed together without additional buffering. Take care to reduce output capacitance, which results in more overshoot and frequency domain peaking.

A series of internal amplifiers drives internal nodes such that a wideband high impedance is presented at the disabled output, even while the output bus is under large signal swings. To keep these internal amplifiers in their linear range of operation when the outputs are disabled and driven externally, do not allow the voltage applied to them to exceed the valid output swing range for the ADV3224/ADV3225. If the disabled outputs are left floating, they may exhibit high enable glitches. If necessary, the disabled output can be kept from drifting out of range by applying an output load resistor to ground.

The connection of the ADV3224/ADV3225 is controlled by a flexible TTL-compatible logic interface. Either parallel or serial loading into a first rank of latches preprograms each output. A global update signal moves the programming data into the second rank of latches, simultaneously updating all outputs. In serial mode, a serial output pin allows devices to be daisy-chained together for single pin programming of multiple ICs. A power-on reset pin is available to avoid bus conflicts by disabling all outputs. This power-on reset clears the second rank of latches but does not clear the first rank of latches. In serial mode, preprogramming individual inputs is not possible and the entire shift register must be flushed.

To easily interface to ground referenced video signals, the ADV3224/ADV3225 operate on split ± 5 V supplies. The logic inputs and output run on a single 5 V supply, and the logic inputs switch at approximately 1.6 V for compatibility with a variety of logic families. The serial output buffer is a rail-to-rail output stage with 5 mA of drive capability.

APPLICATIONS INFORMATION

The ADV3224/ADV3225 have two options for changing the programming of the crosspoint matrix. In the first option, a serial word of 40 bits can be provided, which updates the entire matrix each time the 40-bit word is shifted into the device. The second option allows for changing the programming of a single output via a parallel interface. The serial option requires fewer signals but more time (clock cycles) for changing the programming, whereas the parallel programming technique requires more signals but can change a single output at a time and requires fewer clock cycles to complete the programming.

SERIAL PROGRAMMING

The serial programming mode uses the \overline{CE} , CLK, DATAIN, \overline{UPDATE} , and \overline{SER}/PAR pins. The first step is to assert a low on \overline{SER}/PAR to enable the serial programming mode. \overline{CE} must be low to allow data to be clocked into the device. The \overline{CE} signal can be used to address an individual device when devices are connected in parallel.

The UPDATE signal should be high during the time that data is shifted into the serial port of the device. Although the data still shifts in when UPDATE is low, the transparent, asynchronous latches allow the shifting data to reach the matrix, which causes the matrix to try to update to every intermediate state as defined by the shifting data.

The data at DATAIN is clocked in at every falling edge of CLK, and a total of 40 bits must be shifted in to complete the programming. For each of the eight outputs, there are four bits (D0 to D3) that determine the source of its input. The MSB is shifted in first. A fifth bit (D4) precedes the four input select bits and determines the enabled state of the output. If D4 is low (output disabled), the four associated bits (D0 to D3) do not matter because no input switches to that output.

The most significant output address data is shifted in first, and the remaining addresses follow in sequence until the least significant output address data is shifted in. At this point, $\overline{\text{UPDATE}}$ can be taken low, which programs the device according to the data that was just shifted in. The update registers are asynchronous, and when $\overline{\text{UPDATE}}$ is low (and $\overline{\text{CE}}$ is low), they are transparent.

If more than one ADV3224/ADV3225 device is to be serially programmed in a system, the DATAOUT signal from one device can be connected to the DATAIN of the next device to form a serial chain. Connect all of the CLK, \overline{CE} , \overline{UPDATE} , and \overline{SER}/PAR pins in parallel and operate them as described previously in this section. The serial data is input to the DATAIN pin of the first device of the chain, and it ripples through to the last. Therefore, the data for the last device in the chain should come at the beginning of the programming sequence. The length of the programming sequence (40 bits) is multiplied by the number of devices in the chain.

PARALLEL PROGRAMMING

When using the parallel programming mode, it is not necessary to reprogram the entire device when making changes to the matrix. Parallel programming allows the modification of a single output at a time. Because this takes only one CLK/UPDATE cycle, significant time savings can be realized by using parallel programming.

An important consideration in using parallel programming is that the \overline{RESET} signal does not reset all registers in the ADV3224/ADV3225. When taken low, the \overline{RESET} signal sets each output to the disabled state. This is helpful during power-up to ensure that two parallel outputs are not active at the same time.

After initial power-up, the internal registers in the device generally contain random data, even though the RESET signal was asserted. If parallel programming is used to program one output, that output is properly programmed, but the rest of the device has a random program state depending on the internal register content at power-up. Therefore, when using parallel programming, it is essential that all outputs be programmed to a desired state after power-up to ensure that the programming matrix is always in a known state. From this point, parallel programming can be used to modify either a single output or multiple outputs at one time.

Similarly, if both $\overline{\text{CE}}$ and $\overline{\text{UPDATE}}$ are taken low after initial power-up, the random power-up data in the shift register is programmed into the matrix. Therefore, to prevent programming the crosspoint into an unknown state, do not apply low logic levels to both $\overline{\text{CE}}$ and $\overline{\text{UPDATE}}$ after power is initially applied. To eliminate the possibility of programming the matrix to an unknown state, after initial power-up, program the full shift register one time to a desired state using either serial or parallel programming.

To change the <u>programming of an output</u> via parallel programming, take the $\overline{SER/PAR}$ and \overline{UPDATE} pins high, and take the \overline{CE} pin low. The CLK signal should be in the high state. Place the 3-bit address of the output to be programmed on A0 to A2.

The first four data bits (D0 to D3) contain the information that identifies the input that is programmed to the addressed output. The fifth data bit (D4) determines the enabled state of the output. If D4 is low (output disabled), the data on D0 to D3 does not matter.

After the address and data signals are established, they can be latched into the shift register by pulling the CLK signal low; however, the matrix is not programmed until the $\overline{\text{UPDATE}}$ signal is taken low. In this way, it is possible to latch in new data for several or all of the outputs first via successive negative transitions of CLK while $\overline{\text{UPDATE}}$ is held high and then have all the new data take effect when $\overline{\text{UPDATE}}$ goes low. Use this technique when programming the device for the first time after power-up when using parallel programming. In parallel mode, the CLK pin is level sensitive, whereas in serial mode, it is edge triggered.

POWER-ON RESET

When powering up the ADV3224/ADV3225, it is usually desirable to have the outputs come up in the disabled state. When taken low, the RESET pin causes all outputs to be in the disabled state. However, the RESET signal does not reset all registers in the ADV3224/ADV3225. This is important when operating in the parallel programming mode. Refer to the Parallel Programming section for information about programming internal registers after power-up. Serial programming programs the entire matrix each time; therefore, no special considerations apply.

Because the data in the shift register is random after power-up, it should not be used to program the matrix, or the matrix can enter unknown states. To prevent the matrix from entering unknown states, do not apply logic low signals to both \overline{CE} and \overline{UPDATE} initially after power-up. Instead, first load the shift register with the data and then take \overline{UPDATE} low to program the device.

The $\overline{\text{RESET}}$ pin has a 20 k Ω pull-up resistor to DVCC that can be used to create a simple power-up reset circuit. A capacitor from $\overline{\text{RESET}}$ to ground holds the $\overline{\text{RESET}}$ pin low for a period during which the rest of the device stabilizes. The low condition causes all of the outputs to be disabled. The capacitor then charges through the pull-up resistor to the high state, thereby, allowing full programming capability of the device.

GAIN SELECTION

The 16×8 crosspoints come in two versions, depending on the gain of the analog circuit path. The ADV3224 device is unity gain and can be used for analog logic switching and other applications where unity gain is desired. The ADV3224 outputs have very high impedance when their outputs are disabled.

The ADV3225 can be used for devices that drive a terminated cable with its outputs. This device has a built-in gain of +2 that eliminates the need for a gain of +2 buffer to drive a video line. Its high output disabled impedance minimizes signal degradation when paralleling additional outputs of other crosspoint devices.

CREATING LARGER CROSSPOINT ARRAYS

The ADV3224/ADV3225 are high density building blocks for creating crosspoint arrays of dimensions larger than 16×8 . Various features, such as output disable, chip enable, and gain of +1 and gain of +2 options, are useful for creating larger arrays.

The first consideration in constructing a larger crosspoint is to determine the minimum number of devices that is required. The 16×8 architecture of the ADV3224/ADV3225 contains 128 points, which is a factor of 32 greater than a 4×1 crosspoint

(or multiplexer). The benefits realized in PCB area used, power consumption, and design effort are readily apparent when compared to using multiples of these smaller 4×1 devices.

To obtain the minimum number of required points for a non-blocking crosspoint, multiply the number of inputs by the number of outputs. Nonblocking requires that the programming of a given input to one or more outputs not restrict the availability of that input to be a source for any other outputs. Some nonblocking crosspoint architectures require more than this minimum. In addition, there are blocking architectures that can be constructed with fewer devices than this minimum. These systems have connectivity available on a statistical basis that is determined when designing the overall system.

The basic concept in constructing larger crosspoint arrays is to connect inputs in parallel in a horizontal direction and to wire-OR the outputs together in the vertical direction. The wire-OR connection can be viewed as a tristate multiplex of the two outputs in that only one output is enabled and the other is in a high-Z state. The meaning of horizontal and vertical can best be understood by referring to Figure 65, which illustrates this concept for a 32×16 crosspoint array that uses four ADV3224 or ADV3225 devices.

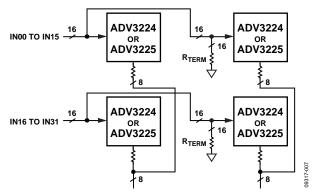


Figure 65. A 32 × 16 Nonblocking Crosspoint Switch Array

Each input is uniquely assigned to each of the 32 inputs of the two devices and terminated appropriately. The outputs are wired-ORèd together in pairs. Enable the output from only one wire-ORèd pair at any given time. The device programming software must be properly written to prevent multiple connected outputs from being enabled at the same time.

Also available are 32×16 arrays in a single package: AD8104, AD8105, ADV3202, and ADV3203. More expansion options are possible using the ADV3226 and ADV3227 wideband 16×16 arrays. For a complete 32×32 array in a single device, use the AD8117 and AD8118 for wide bandwidth or the ADV3200 and ADV3201 for less bandwidth.

OUTLINE DIMENSIONS

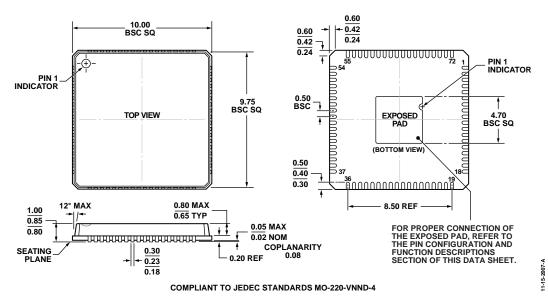


Figure 66. 72-Lead Lead Frame Chip Scale Package [LFCSP_VQ] 10 mm × 10 mm Body, Very Thin Quad (CP-72-1) Dimensions shown in millimeters

ORDERING GUIDE

| Model ¹ | Temperature Range | Package Description | Package Option |
|--------------------|-------------------|--|----------------|
| ADV3224ACPZ | -40°C to +85°C | 72-Lead Lead Frame Chip Scale Package [LFCSP_VQ] | CP-72-1 |
| ADV3224-EVALZ | | Evaluation Board | |
| ADV3225ACPZ | -40°C to +85°C | 72-Lead Lead Frame Chip Scale Package [LFCSP_VQ] | CP-72-1 |
| ADV3225-EVALZ | | Evaluation Board | |

 $^{^{1}}$ Z = RoHS Compliant Part.